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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

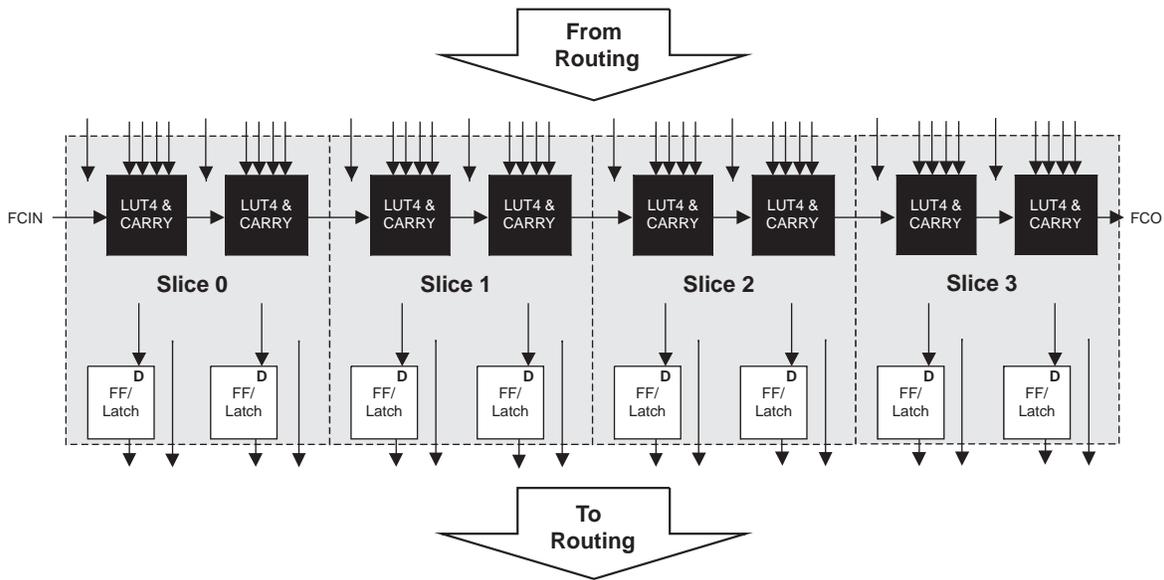
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	264
Number of Logic Elements/Cells	2112
Total RAM Bits	94208
Number of I/O	278
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo2-2000uhe-4fg484i

Figure 2-3. PFU Block Diagram



Slices

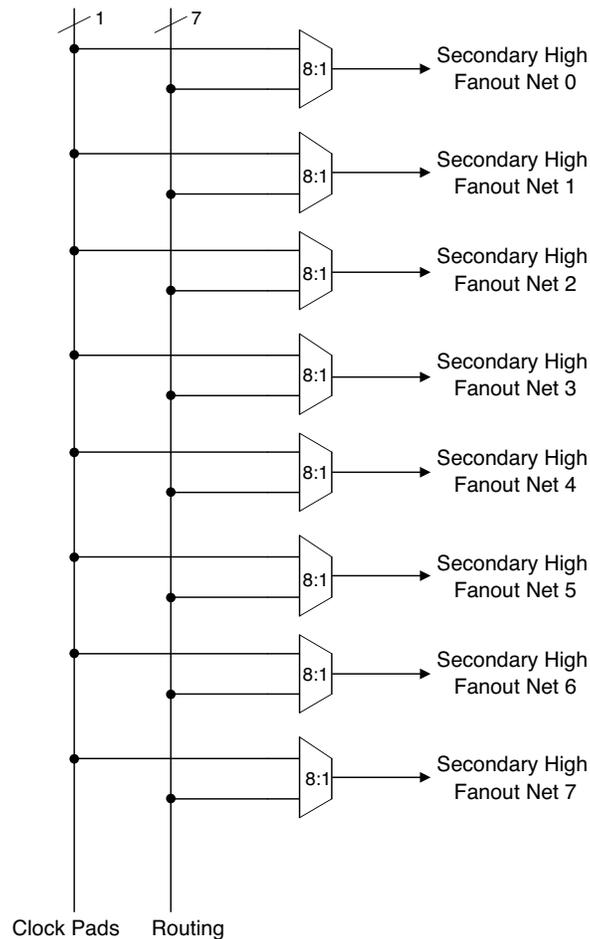
Slices 0-3 contain two LUT4s feeding two registers. Slices 0-2 can be configured as distributed memory. Table 2-1 shows the capability of the slices in PFU blocks along with the operation modes they enable. In addition, each PFU contains logic that allows the LUTs to be combined to perform functions such as LUT5, LUT6, LUT7 and LUT8. The control logic performs set/reset functions (programmable as synchronous/ asynchronous), clock select, chip-select and wider RAM/ROM functions.

Table 2-1. Resources and Modes Available per Slice

Slice	PFU Block	
	Resources	Modes
Slice 0	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 1	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 2	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 3	2 LUT4s and 2 Registers	Logic, Ripple, ROM

Figure 2-4 shows an overview of the internal logic of the slice. The registers in the slice can be configured for positive/negative and edge triggered or level sensitive clocks. All slices have 15 inputs from routing and one from the carry-chain (from the adjacent slice or PFU). There are seven outputs: six for routing and one to carry-chain (to the adjacent PFU). Table 2-2 lists the signals associated with Slices 0-3.

Figure 2-6. Secondary High Fanout Nets for MachXO2 Devices



sysCLOCK Phase Locked Loops (PLLs)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The MachXO2-640U, MachXO2-1200/U and larger devices have one or more sysCLOCK PLL. CLKI is the reference frequency input to the PLL and its source can come from an external I/O pin or from internal routing. CLKFB is the feedback signal to the PLL which can come from internal routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The MachXO2 sysCLOCK PLLs support high resolution (16-bit) fractional-N synthesis. Fractional-N frequency synthesis allows the user to generate an output clock which is a non-integer multiple of the input frequency. For more information about using the PLL with Fractional-N synthesis, please see TN1199, [MachXO2 sysCLOCK PLL Design and Usage Guide](#).

Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The output dividers may also be cascaded together to generate low frequency clocks. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the MachXO2 clock distribution network directly or general purpose routing resources can be used.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected. A block diagram of the PLL is shown in Figure 2-7.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock.

Table 2-4. PLL Signal Descriptions (Continued)

Port Name	I/O	Description
CLKOP	O	Primary PLL output clock (with phase shift adjustment)
CLKOS	O	Secondary PLL output clock (with phase shift adjust)
CLKOS2	O	Secondary PLL output clock2 (with phase shift adjust)
CLKOS3	O	Secondary PLL output clock3 (with phase shift adjust)
LOCK	O	PLL LOCK, asynchronous signal. Active high indicates PLL is locked to input and feedback signals.
DPHSRC	O	Dynamic Phase source – ports or WISHBONE is active
STDBY	I	Standby signal to power down the PLL
RST	I	PLL reset without resetting the M-divider. Active high reset.
RESETM	I	PLL reset - includes resetting the M-divider. Active high reset.
RESETC	I	Reset for CLKOS2 output divider only. Active high reset.
RESETD	I	Reset for CLKOS3 output divider only. Active high reset.
ENCLKOP	I	Enable PLL output CLKOP
ENCLKOS	I	Enable PLL output CLKOS when port is active
ENCLKOS2	I	Enable PLL output CLKOS2 when port is active
ENCLKOS3	I	Enable PLL output CLKOS3 when port is active
PLLCLK	I	PLL data bus clock input signal
PLL_RST	I	PLL data bus reset. This resets only the data bus not any register values.
PLLSTB	I	PLL data bus strobe signal
PLLWE	I	PLL data bus write enable signal
PLLADDR [4:0]	I	PLL data bus address
PLLDATI [7:0]	I	PLL data bus data input
PLLDATO [7:0]	O	PLL data bus data output
PLLACK	O	PLL data bus acknowledge signal

sysMEM Embedded Block RAM Memory

The MachXO2-640/U and larger devices contain sysMEM Embedded Block RAMs (EBRs). The EBR consists of a 9-kbit RAM, with dedicated input and output registers. This memory can be used for a wide variety of purposes including data buffering, PROM for the soft processor and FIFO.

sysMEM Memory Block

The sysMEM block can implement single port, dual port, pseudo dual port, or FIFO memories. Each block can be used in a variety of depths and widths as shown in Table 2-5.

The EBR memory supports three forms of write behavior for single or dual port operation:

1. **Normal** – Data on the output appears only during the read cycle. During a write cycle, the data (at the current address) does not appear on the output. This mode is supported for all data widths.
2. **Write Through** – A copy of the input data appears at the output of the same port. This mode is supported for all data widths.
3. **Read-Before-Write** – When new data is being written, the old contents of the address appears at the output.

FIFO Configuration

The FIFO has a write port with data-in, CEW, WE and CLKW signals. There is a separate read port with data-out, RCE, RE and CLKR signals. The FIFO internally generates Almost Full, Full, Almost Empty and Empty Flags. The Full and Almost Full flags are registered with CLKW. The Empty and Almost Empty flags are registered with CLKR. Table 2-7 shows the range of programming values for these flags.

Table 2-7. Programmable FIFO Flag Ranges

Flag Name	Programming Range
Full (FF)	1 to max (up to 2^N-1)
Almost Full (AF)	1 to Full-1
Almost Empty (AE)	1 to Full-1
Empty (EF)	0

N = Address bit width.

The FIFO state machine supports two types of reset signals: RST and RPRST. The RST signal is a global reset that clears the contents of the FIFO by resetting the read/write pointer and puts the FIFO flags in their initial reset state. The RPRST signal is used to reset the read pointer. The purpose of this reset is to retransmit the data that is in the FIFO. In these applications it is important to keep careful track of when a packet is written into or read from the FIFO.

Memory Core Reset

The memory core contains data output latches for ports A and B. These are simple latches that can be reset synchronously or asynchronously. RSTA and RSTB are local signals, which reset the output latches associated with port A and port B respectively. The Global Reset (GSRN) signal resets both ports. The output data latches and associated resets for both ports are as shown in Figure 2-9.

Programmable I/O Cells (PIC)

The programmable logic associated with an I/O is called a PIO. The individual PIO are connected to their respective sysIO buffers and pads. On the MachXO2 devices, the PIO cells are assembled into groups of four PIO cells called a Programmable I/O Cell or PIC. The PICs are placed on all four sides of the device.

On all the MachXO2 devices, two adjacent PIOs can be combined to provide a complementary output driver pair.

The MachXO2-640U, MachXO2-1200/U and higher density devices contain enhanced I/O capability. All PIO pairs on these larger devices can implement differential receivers. Half of the PIO pairs on the top edge of these devices can be configured as true LVDS transmit pairs. The PIO pairs on the bottom edge of these higher density devices have on-chip differential termination and also provide PCI support.

When implementing background programming of the on-chip Flash, care must be taken for the operation of the PLL. For devices that have two PLLs (XO2-2000U, -4000 and -7000), the system must put the RPLL (Right-side PLL) in reset state during the background Flash programming. More detailed description can be found in TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

Security and One-Time Programmable Mode (OTP)

For applications where security is important, the lack of an external bitstream provides a solution that is inherently more secure than SRAM-based FPGAs. This is further enhanced by device locking. MachXO2 devices contain security bits that, when set, prevent the readback of the SRAM configuration and non-volatile Flash memory spaces. The device can be in one of two modes:

1. Unlocked – Readback of the SRAM configuration and non-volatile Flash memory spaces is allowed.
2. Permanently Locked – The device is permanently locked.

Once set, the only way to clear the security bits is to erase the device. To further complement the security of the device, a One Time Programmable (OTP) mode is available. Once the device is set in this mode it is not possible to erase or re-program the Flash and SRAM OTP portions of the device. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

Dual Boot

MachXO2 devices can optionally boot from two patterns, a primary bitstream and a golden bitstream. If the primary bitstream is found to be corrupt while being downloaded into the SRAM, the device shall then automatically re-boot from the golden bitstream. Note that the primary bitstream must reside in the on-chip Flash. The golden image MUST reside in an external SPI Flash. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

Soft Error Detection

The SED feature is a CRC check of the SRAM cells after the device is configured. This check ensures that the SRAM cells were configured successfully. This feature is enabled by a configuration bit option. The Soft Error Detection can also be initiated in user mode via an input to the fabric. The clock for the Soft Error Detection circuit is generated using a dedicated divider. The undivided clock from the on-chip oscillator is the input to this divider. For low power applications users can switch off the Soft Error Detection circuit. For more details, refer to TN1206, [MachXO2 Soft Error Detection Usage Guide](#).

TracelD

Each MachXO2 device contains a unique (per device), TracelD that can be used for tracking purposes or for IP security applications. The TracelD is 64 bits long. Eight out of 64 bits are user-programmable, the remaining 56 bits are factory-programmed. The TracelD is accessible through the EFB WISHBONE interface and can also be accessed through the SPI, I²C, or JTAG interfaces.

Density Shifting

The MachXO2 family has been designed to enable density migration within the same package. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likely success in each case. When migrating from lower to higher density or higher to lower density, ensure to review all the power supplies and NC pins of the chosen devices. For more details refer to the [MachXO2 migration files](#).

DC Electrical Characteristics

Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$I_{IL}, I_{IH}^{1,4}$	Input or I/O Leakage	Clamp OFF and $V_{CCIO} < V_{IN} < V_{IH} (MAX)$	—	—	+175	μA
		Clamp OFF and $V_{IN} = V_{CCIO}$	-10	—	10	μA
		Clamp OFF and $V_{CCIO} - 0.97 V < V_{IN} < V_{CCIO}$	-175	—	—	μA
		Clamp OFF and $0 V < V_{IN} < V_{CCIO} - 0.97 V$	—	—	10	μA
		Clamp OFF and $V_{IN} = GND$	—	—	10	μA
		Clamp ON and $0 V < V_{IN} < V_{CCIO}$	—	—	10	μA
I_{PU}	I/O Active Pull-up Current	$0 < V_{IN} < 0.7 V_{CCIO}$	-30	—	-309	μA
I_{PD}	I/O Active Pull-down Current	$V_{IL} (MAX) < V_{IN} < V_{CCIO}$	30	—	305	μA
I_{BHLS}	Bus Hold Low sustaining current	$V_{IN} = V_{IL} (MAX)$	30	—	—	μA
I_{BHHS}	Bus Hold High sustaining current	$V_{IN} = 0.7V_{CCIO}$	-30	—	—	μA
I_{BHLO}	Bus Hold Low Overdrive current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	305	μA
I_{BHHO}	Bus Hold High Overdrive current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	-309	μA
V_{BHT}^3	Bus Hold Trip Points		$V_{IL} (MAX)$	—	$V_{IH} (MIN)$	V
C1	I/O Capacitance ²	$V_{CCIO} = 3.3 V, 2.5 V, 1.8 V, 1.5 V, 1.2 V, V_{CC} = Typ., V_{IO} = 0 \text{ to } V_{IH} (MAX)$	3	5	9	pF
C2	Dedicated Input Capacitance ²	$V_{CCIO} = 3.3 V, 2.5 V, 1.8 V, 1.5 V, 1.2 V, V_{CC} = Typ., V_{IO} = 0 \text{ to } V_{IH} (MAX)$	3	5.5	7	pF
V_{HYST}	Hysteresis for Schmitt Trigger Inputs ⁵	$V_{CCIO} = 3.3 V, \text{Hysteresis} = \text{Large}$	—	450	—	mV
		$V_{CCIO} = 2.5 V, \text{Hysteresis} = \text{Large}$	—	250	—	mV
		$V_{CCIO} = 1.8 V, \text{Hysteresis} = \text{Large}$	—	125	—	mV
		$V_{CCIO} = 1.5 V, \text{Hysteresis} = \text{Large}$	—	100	—	mV
		$V_{CCIO} = 3.3 V, \text{Hysteresis} = \text{Small}$	—	250	—	mV
		$V_{CCIO} = 2.5 V, \text{Hysteresis} = \text{Small}$	—	150	—	mV
		$V_{CCIO} = 1.8 V, \text{Hysteresis} = \text{Small}$	—	60	—	mV
		$V_{CCIO} = 1.5 V, \text{Hysteresis} = \text{Small}$	—	40	—	mV

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.
2. T_A 25 °C, $f = 1.0$ MHz.
3. Please refer to V_{IL} and V_{IH} in the sysIO Single-Ended DC Electrical Characteristics table of this document.
4. When V_{IH} is higher than V_{CCIO} , a transient current typically of 30 ns in duration or less with a peak current of 6 mA can occur on the high-to-low transition. For true LVDS output pins in MachXO2-640U, MachXO2-1200/U and larger devices, V_{IH} must be less than or equal to V_{CCIO} .
5. With bus keeper circuit turned on. For more details, refer to TN1202, [MachXO2 sysIO Usage Guide](#).

RSDS

The MachXO2 family supports the differential RSDS standard. The output standard is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all the devices. The RSDS input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-4 is one possible solution for RSDS standard implementation. Use LVDS25E mode with suggested resistors for RSDS operation. Resistor values in Figure 3-4 are industry standard values for 1% resistors.

Figure 3-4. RSDS (Reduced Swing Differential Standard)

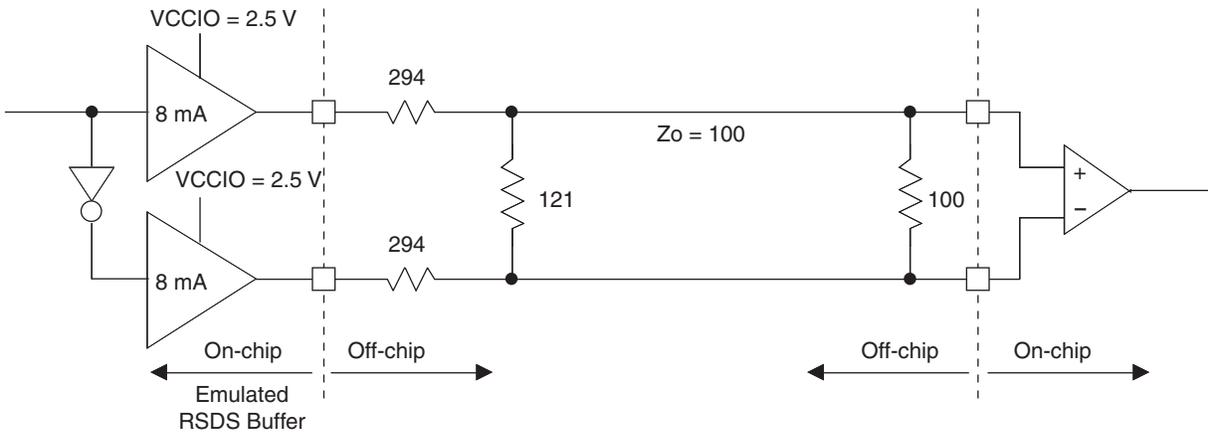


Table 3-4. RSDS DC Conditions

Parameter	Description	Typical	Units
Z_{OUT}	Output impedance	20	Ohms
R_S	Driver series resistor	294	Ohms
R_P	Driver parallel resistor	121	Ohms
R_T	Receiver termination	100	Ohms
V_{OH}	Output high voltage	1.35	V
V_{OL}	Output low voltage	1.15	V
V_{OD}	Output differential voltage	0.20	V
V_{CM}	Output common mode voltage	1.25	V
Z_{BACK}	Back impedance	101.5	Ohms
I_{DC}	DC output current	3.66	mA

Maximum sysIO Buffer Performance

I/O Standard	Max. Speed	Units
LVDS25	400	MHz
LVDS25E	150	MHz
RSDS25	150	MHz
RSDS25E	150	MHz
BLVDS25	150	MHz
BLVDS25E	150	MHz
MLVDS25	150	MHz
MLVDS25E	150	MHz
LVPECL33	150	MHz
LVPECL33E	150	MHz
SSTL25_I	150	MHz
SSTL25_II	150	MHz
SSTL25D_I	150	MHz
SSTL25D_II	150	MHz
SSTL18_I	150	MHz
SSTL18_II	150	MHz
SSTL18D_I	150	MHz
SSTL18D_II	150	MHz
HSTL18_I	150	MHz
HSTL18_II	150	MHz
HSTL18D_I	150	MHz
HSTL18D_II	150	MHz
PCI33	134	MHz
LVTTL33	150	MHz
LVTTL33D	150	MHz
LVC MOS33	150	MHz
LVC MOS33D	150	MHz
LVC MOS25	150	MHz
LVC MOS25D	150	MHz
LVC MOS25R33	150	MHz
LVC MOS18	150	MHz
LVC MOS18D	150	MHz
LVC MOS18R33	150	MHz
LVC MOS18R25	150	MHz
LVC MOS15	150	MHz
LVC MOS15D	150	MHz
LVC MOS15R33	150	MHz
LVC MOS15R25	150	MHz
LVC MOS12	91	MHz
LVC MOS12D	91	MHz

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{HPLL}	Clock to Data Hold – PIO Input Register	MachXO2-1200HC-HE	0.41	—	0.48	—	0.55	—	ns
		MachXO2-2000HC-HE	0.42	—	0.49	—	0.56	—	ns
		MachXO2-4000HC-HE	0.43	—	0.50	—	0.58	—	ns
		MachXO2-7000HC-HE	0.46	—	0.54	—	0.62	—	ns
t _{SU_DELPLL}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200HC-HE	2.88	—	3.19	—	3.72	—	ns
		MachXO2-2000HC-HE	2.87	—	3.18	—	3.70	—	ns
		MachXO2-4000HC-HE	2.96	—	3.28	—	3.81	—	ns
		MachXO2-7000HC-HE	3.05	—	3.35	—	3.87	—	ns
t _{H_DELPLL}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200HC-HE	-0.83	—	-0.83	—	-0.83	—	ns
		MachXO2-2000HC-HE	-0.83	—	-0.83	—	-0.83	—	ns
		MachXO2-4000HC-HE	-0.87	—	-0.87	—	-0.87	—	ns
		MachXO2-7000HC-HE	-0.91	—	-0.91	—	-0.91	—	ns
Generic DDRX1 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDRX1_RX.SCLK.Aligned^{9, 12}									
t _{DVA}	Input Data Valid After CLK	All MachXO2 devices, all sides	—	0.317	—	0.344	—	0.368	UI
t _{DVE}	Input Data Hold After CLK		0.742	—	0.702	—	0.668	—	UI
f _{DATA}	DDRX1 Input Data Speed		—	300	—	250	—	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency		—	150	—	125	—	104	MHz
Generic DDRX1 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX1_RX.SCLK.Centered^{9, 12}									
t _{SU}	Input Data Setup Before CLK	All MachXO2 devices, all sides	0.566	—	0.560	—	0.538	—	ns
t _{HO}	Input Data Hold After CLK		0.778	—	0.879	—	1.090	—	ns
f _{DATA}	DDRX1 Input Data Speed		—	300	—	250	—	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency		—	150	—	125	—	104	MHz
Generic DDRX2 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDRX2_RX.ECLK.Aligned^{9, 12}									
t _{DVA}	Input Data Valid After CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	—	0.316	—	0.342	—	0.364	UI
t _{DVE}	Input Data Hold After CLK		0.710	—	0.675	—	0.679	—	UI
f _{DATA}	DDRX2 Serial Input Data Speed		—	664	—	554	—	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency		—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		—	166	—	139	—	116	MHz
Generic DDRX2 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX2_RX.ECLK.Centered^{9, 12}									
t _{SU}	Input Data Setup Before CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	0.233	—	0.219	—	0.198	—	ns
t _{HO}	Input Data Hold After CLK		0.287	—	0.287	—	0.344	—	ns
f _{DATA}	DDRX2 Serial Input Data Speed		—	664	—	554	—	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency		—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		—	166	—	139	—	116	MHz

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{HPLL}	Clock to Data Hold – PIO Input Register	MachXO2-1200ZE	0.66	—	0.68	—	0.80	—	ns
		MachXO2-2000ZE	0.68	—	0.70	—	0.83	—	ns
		MachXO2-4000ZE	0.68	—	0.71	—	0.84	—	ns
		MachXO2-7000ZE	0.73	—	0.74	—	0.87	—	ns
t _{SU_DELPLL}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200ZE	5.14	—	5.69	—	6.20	—	ns
		MachXO2-2000ZE	5.11	—	5.67	—	6.17	—	ns
		MachXO2-4000ZE	5.27	—	5.84	—	6.35	—	ns
		MachXO2-7000ZE	5.15	—	5.71	—	6.23	—	ns
t _{H_DELPLL}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200ZE	-1.36	—	-1.36	—	-1.36	—	ns
		MachXO2-2000ZE	-1.35	—	-1.35	—	-1.35	—	ns
		MachXO2-4000ZE	-1.43	—	-1.43	—	-1.43	—	ns
		MachXO2-7000ZE	-1.41	—	-1.41	—	-1.41	—	ns
Generic DDRX1 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Aligned^{9,12}									
t _{DVA}	Input Data Valid After CLK	All MachXO2 devices, all sides	—	0.382	—	0.401	—	0.417	UI
t _{DVE}	Input Data Hold After CLK		0.670	—	0.684	—	0.693	—	UI
f _{DATA}	DDR1 Input Data Speed		—	140	—	116	—	98	Mbps
f _{DDR1}	DDR1 SCLK Frequency		—	70	—	58	—	49	MHz
Generic DDRX1 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Centered^{9,12}									
t _{SU}	Input Data Setup Before CLK	All MachXO2 devices, all sides	1.319	—	1.412	—	1.462	—	ns
t _{HO}	Input Data Hold After CLK		0.717	—	1.010	—	1.340	—	ns
f _{DATA}	DDR1 Input Data Speed		—	140	—	116	—	98	Mbps
f _{DDR1}	DDR1 SCLK Frequency		—	70	—	58	—	49	MHz
Generic DDRX2 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Aligned^{9,12}									
t _{DVA}	Input Data Valid After CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	—	0.361	—	0.346	—	0.334	UI
t _{DVE}	Input Data Hold After CLK		0.602	—	0.625	—	0.648	—	UI
f _{DATA}	DDR2 Serial Input Data Speed		—	280	—	234	—	194	Mbps
f _{DDR2}	DDR2 ECLK Frequency		—	140	—	117	—	97	MHz
f _{SCLK}	SCLK Frequency		—	70	—	59	—	49	MHz
Generic DDRX2 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Centered^{9,12}									
t _{SU}	Input Data Setup Before CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	0.472	—	0.672	—	0.865	—	ns
t _{HO}	Input Data Hold After CLK		0.363	—	0.501	—	0.743	—	ns
f _{DATA}	DDR2 Serial Input Data Speed		—	280	—	234	—	194	Mbps
f _{DDR2}	DDR2 ECLK Frequency		—	140	—	117	—	97	MHz
f _{SCLK}	SCLK Frequency		—	70	—	59	—	49	MHz
Generic DDR4 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input - GDDR4_RX.ECLK.Aligned^{9,12}									
t _{DVA}	Input Data Valid After ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	—	0.307	—	0.316	—	0.326	UI
t _{DVE}	Input Data Hold After ECLK		0.662	—	0.650	—	0.649	—	UI
f _{DATA}	DDR4 Serial Input Data Speed		—	420	—	352	—	292	Mbps
f _{DDR4}	DDR4 ECLK Frequency		—	210	—	176	—	146	MHz
f _{SCLK}	SCLK Frequency		—	53	—	44	—	37	MHz

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
LPDDR^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.349	—	0.381	—	0.396	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.665	—	0.630	—	0.613	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM LPDDR Serial Data Speed		—	120	—	110	—	96	Mbps
f _{SCLK}	SCLK Frequency		—	60	—	55	—	48	MHz
f _{LPDDR}	LPDDR Data Transfer Rate		0	120	0	110	0	96	Mbps
DDR^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.347	—	0.374	—	0.393	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.665	—	0.637	—	0.616	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f _{SCLK}	SCLK Frequency		—	70	—	58	—	49	MHz
f _{MEM_DDR}	MEM DDR Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps
DDR2^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.372	—	0.394	—	0.410	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.690	—	0.658	—	0.618	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f _{SCLK}	SCLK Frequency		—	70	—	58	—	49	MHz
f _{MEM_DDR2}	MEM DDR2 Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps

1. Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.
2. General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0 pF load, fast slew rate.
3. Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).
4. DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18. LPDDR timing numbers based in LVCMOS18.
5. 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).
6. For Generic DDRX1 mode $t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 \text{ ns})/2$.
7. The t_{SU_DEL} and t_{H_DEL} values use the SCLK_ZERHOLD default step size. Each step is 167 ps (-3), 182 ps (-2), 195 ps (-1).
8. This number for general purpose usage. Duty cycle tolerance is +/-10%.
9. Duty cycle is +/- 5% for system usage.
10. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.
11. High-speed DDR and LVDS not supported in SG32 (32-Pin QFN) packages.
12. Advance information for MachXO2 devices in 48 QFN packages.
13. DDR memory interface not supported in QN84 (84 QFN) and SG32 (32 QFN) packages.

Figure 3-5. Receiver RX.CLK.Aligned and MEM DDR Input Waveforms

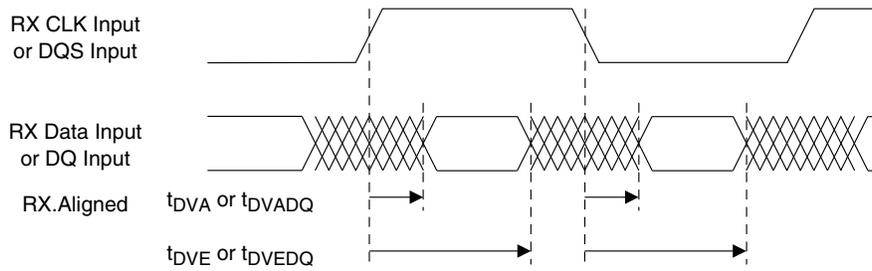


Figure 3-6. Receiver RX.CLK.Centered Waveforms

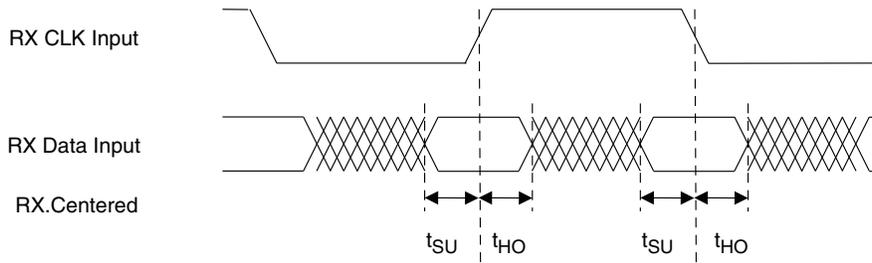


Figure 3-7. Transmitter TX.CLK.Aligned Waveforms

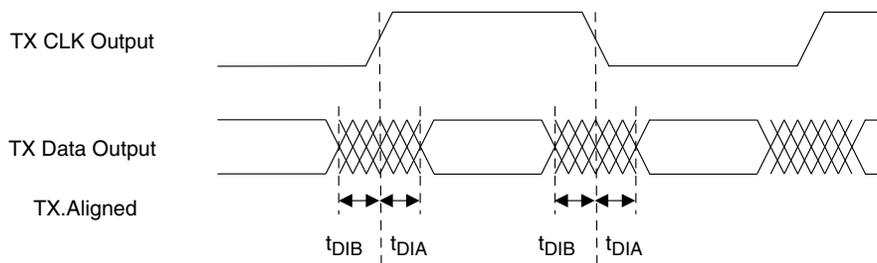
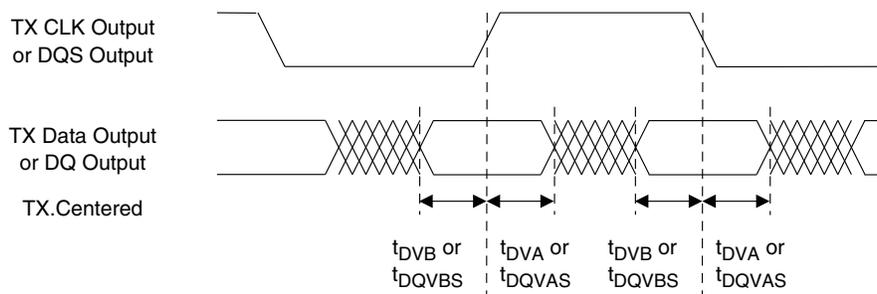


Figure 3-8. Transmitter TX.CLK.Centered and MEM DDR Output Waveforms



Flash Download Time^{1, 2}

Symbol	Parameter	Device	Typ.	Units
t_{REFRESH}	POR to Device I/O Active	LCMXO2-256	0.6	ms
		LCMXO2-640	1.0	ms
		LCMXO2-640U	1.9	ms
		LCMXO2-1200	1.9	ms
		LCMXO2-1200U	1.4	ms
		LCMXO2-2000	1.4	ms
		LCMXO2-2000U	2.4	ms
		LCMXO2-4000	2.4	ms
		LCMXO2-7000	3.8	ms

1. Assumes sysMEM EBR initialized to an all zero pattern if they are used.
2. The Flash download time is measured starting from the maximum voltage of POR trip point.

JTAG Port Timing Specifications

Symbol	Parameter	Min.	Max.	Units
f_{MAX}	TCK clock frequency	—	25	MHz
t_{BTCPH}	TCK [BSCAN] clock pulse width high	20	—	ns
t_{BTCPL}	TCK [BSCAN] clock pulse width low	20	—	ns
t_{BTS}	TCK [BSCAN] setup time	10	—	ns
t_{BTH}	TCK [BSCAN] hold time	8	—	ns
t_{BTCO}	TAP controller falling edge of clock to valid output	—	10	ns
t_{BTCODIS}	TAP controller falling edge of clock to valid disable	—	10	ns
t_{BTCOEN}	TAP controller falling edge of clock to valid enable	—	10	ns
t_{BTCRS}	BSCAN test capture register setup time	8	—	ns
t_{BTCRH}	BSCAN test capture register hold time	20	—	ns
t_{BUTCO}	BSCAN test update register, falling edge of clock to valid output	—	25	ns
t_{BTUODIS}	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
t_{BTUPOEN}	BSCAN test update register, falling edge of clock to valid enable	—	25	ns

	MachXO2-4000							
	84 QFN	132 csBGA	144 TQFP	184 csBGA	256 caBGA	256 ftBGA	332 caBGA	484 fpBGA
General Purpose I/O per Bank								
Bank 0	27	25	27	37	50	50	68	70
Bank 1	10	26	29	37	52	52	68	68
Bank 2	22	28	29	39	52	52	70	72
Bank 3	0	7	9	10	16	16	24	24
Bank 4	9	8	10	12	16	16	16	16
Bank 5	0	10	10	15	20	20	28	28
Total General Purpose Single Ended I/O	68	104	114	150	206	206	274	278
Differential I/O per Bank								
Bank 0	13	13	14	18	25	25	34	35
Bank 1	4	13	14	18	26	26	34	34
Bank 2	11	14	14	19	26	26	35	36
Bank 3	0	3	4	4	8	8	12	12
Bank 4	4	4	5	6	8	8	8	8
Bank 5	0	5	5	7	10	10	14	14
Total General Purpose Differential I/O	32	52	56	72	103	103	137	139
Dual Function I/O								
	28	37	37	37	37	37	37	37
High-speed Differential I/O								
Bank 0	8	8	9	8	18	18	18	18
Gearboxes								
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	8	8	9	9	18	18	18	18
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	11	14	14	12	18	18	18	18
DQS Groups								
Bank 1	1	2	2	2	2	2	2	2
VCCIO Pins								
Bank 0	3	3	3	3	4	4	4	10
Bank 1	1	3	3	3	4	4	4	10
Bank 2	2	3	3	3	4	4	4	10
Bank 3	1	1	1	1	1	1	2	3
Bank 4	1	1	1	1	2	2	1	4
Bank 5	1	1	1	1	1	1	2	3
VCC	4	4	4	4	8	8	8	12
GND	4	10	12	16	24	24	27	48
NC	1	1	1	1	1	1	5	105
Reserved for configuration	1	1	1	1	1	1	1	1
Total Count of Bonded Pins	84	132	144	184	256	256	332	484

	MachXO2-7000					
	144 TQFP	256 caBGA	256 ftBGA	332 caBGA	400 caBGA	484 fpBGA
General Purpose I/O per Bank						
Bank 0	27	50	50	68	83	82
Bank 1	29	52	52	70	84	84
Bank 2	29	52	52	70	84	84
Bank 3	9	16	16	24	28	28
Bank 4	10	16	16	16	24	24
Bank 5	10	20	20	30	32	32
Total General Purpose Single Ended I/O	114	206	206	278	335	334
Differential I/O per Bank						
Bank 0	14	25	25	34	42	41
Bank 1	14	26	26	35	42	42
Bank 2	14	26	26	35	42	42
Bank 3	4	8	8	12	14	14
Bank 4	5	8	8	8	12	12
Bank 5	5	10	10	15	16	16
Total General Purpose Differential I/O	56	103	103	139	168	167
Dual Function I/O						
	37	37	37	37	37	37
High-speed Differential I/O						
Bank 0	9	20	20	21	21	21
Gearboxes						
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	9	20	20	21	21	21
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	14	20	20	21	21	21
DQS Groups						
Bank 1	2	2	2	2	2	2
VCCIO Pins						
Bank 0	3	4	4	4	5	10
Bank 1	3	4	4	4	5	10
Bank 2	3	4	4	4	5	10
Bank 3	1	1	1	2	2	3
Bank 4	1	2	2	1	2	4
Bank 5	1	1	1	2	2	3
VCC	4	8	8	8	10	12
GND	12	24	24	27	33	48
NC	1	1	1	1	0	49
Reserved for Configuration	1	1	1	1	1	1
Total Count of Bonded Pins	144	256	256	332	400	484

Ordering Information

MachXO2 devices have top-side markings, for commercial and industrial grades, as shown below:

LATTICE LCMXO2-1200ZE 1TG100C Datecode	LCMXO2 256ZE 1UG64C Datecode
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Notes:

1. *Markings are abbreviated for small packages.*
2. See [PCN 05A-12](#) for information regarding a change to the top-side mark logo.

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000ZE-1TG144C	6864	1.2 V	-1	Halogen-Free TQFP	144	COM
LCMXO2-7000ZE-2TG144C	6864	1.2 V	-2	Halogen-Free TQFP	144	COM
LCMXO2-7000ZE-3TG144C	6864	1.2 V	-3	Halogen-Free TQFP	144	COM
LCMXO2-7000ZE-1BG256C	6864	1.2 V	-1	Halogen-Free caBGA	256	COM
LCMXO2-7000ZE-2BG256C	6864	1.2 V	-2	Halogen-Free caBGA	256	COM
LCMXO2-7000ZE-3BG256C	6864	1.2 V	-3	Halogen-Free caBGA	256	COM
LCMXO2-7000ZE-1FTG256C	6864	1.2 V	-1	Halogen-Free ftBGA	256	COM
LCMXO2-7000ZE-2FTG256C	6864	1.2 V	-2	Halogen-Free ftBGA	256	COM
LCMXO2-7000ZE-3FTG256C	6864	1.2 V	-3	Halogen-Free ftBGA	256	COM
LCMXO2-7000ZE-1BG332C	6864	1.2 V	-1	Halogen-Free caBGA	332	COM
LCMXO2-7000ZE-2BG332C	6864	1.2 V	-2	Halogen-Free caBGA	332	COM
LCMXO2-7000ZE-3BG332C	6864	1.2 V	-3	Halogen-Free caBGA	332	COM
LCMXO2-7000ZE-1FG484C	6864	1.2 V	-1	Halogen-Free fpBGA	484	COM
LCMXO2-7000ZE-2FG484C	6864	1.2 V	-2	Halogen-Free fpBGA	484	COM
LCMXO2-7000ZE-3FG484C	6864	1.2 V	-3	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200ZE-1TG100CR1 ¹	1280	1.2 V	-1	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-2TG100CR1 ¹	1280	1.2 V	-2	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-3TG100CR1 ¹	1280	1.2 V	-3	Halogen-Free TQFP	100	COM
LCMXO2-1200ZE-1MG132CR1 ¹	1280	1.2 V	-1	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-2MG132CR1 ¹	1280	1.2 V	-2	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-3MG132CR1 ¹	1280	1.2 V	-3	Halogen-Free csBGA	132	COM
LCMXO2-1200ZE-1TG144CR1 ¹	1280	1.2 V	-1	Halogen-Free TQFP	144	COM
LCMXO2-1200ZE-2TG144CR1 ¹	1280	1.2 V	-2	Halogen-Free TQFP	144	COM
LCMXO2-1200ZE-3TG144CR1 ¹	1280	1.2 V	-3	Halogen-Free TQFP	144	COM

1. Specifications for the “LCMXO2-1200ZE-speed package CR1” are the same as the “LCMXO2-1200ZE-speed package C” devices respectively, except as specified in the [R1 Device Specifications](#) section of this data sheet.

High-Performance Commercial Grade Devices without Voltage Regulator, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HE-4TG100C	2112	1.2 V	-4	Halogen-Free TQFP	100	COM
LCMXO2-2000HE-5TG100C	2112	1.2 V	-5	Halogen-Free TQFP	100	COM
LCMXO2-2000HE-6TG100C	2112	1.2 V	-6	Halogen-Free TQFP	100	COM
LCMXO2-2000HE-4TG144C	2112	1.2 V	-4	Halogen-Free TQFP	144	COM
LCMXO2-2000HE-5TG144C	2112	1.2 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-2000HE-6TG144C	2112	1.2 V	-6	Halogen-Free TQFP	144	COM
LCMXO2-2000HE-4MG132C	2112	1.2 V	-4	Halogen-Free csBGA	132	COM
LCMXO2-2000HE-5MG132C	2112	1.2 V	-5	Halogen-Free csBGA	132	COM
LCMXO2-2000HE-6MG132C	2112	1.2 V	-6	Halogen-Free csBGA	132	COM
LCMXO2-2000HE-4BG256C	2112	1.2 V	-4	Halogen-Free caBGA	256	COM
LCMXO2-2000HE-5BG256C	2112	1.2 V	-5	Halogen-Free caBGA	256	COM
LCMXO2-2000HE-6BG256C	2112	1.2 V	-6	Halogen-Free caBGA	256	COM
LCMXO2-2000HE-4FTG256C	2112	1.2 V	-4	Halogen-Free ftBGA	256	COM
LCMXO2-2000HE-5FTG256C	2112	1.2 V	-5	Halogen-Free ftBGA	256	COM
LCMXO2-2000HE-6FTG256C	2112	1.2 V	-6	Halogen-Free ftBGA	256	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHE-4FG484C	2112	1.2 V	-4	Halogen-Free fpBGA	484	COM
LCMXO2-2000UHE-5FG484C	2112	1.2 V	-5	Halogen-Free fpBGA	484	COM
LCMXO2-2000UHE-6FG484C	2112	1.2 V	-6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000HE-4TG144C	4320	1.2 V	-4	Halogen-Free TQFP	144	COM
LCMXO2-4000HE-5TG144C	4320	1.2 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-4000HE-6TG144C	4320	1.2 V	-6	Halogen-Free TQFP	144	COM
LCMXO2-4000HE-4MG132C	4320	1.2 V	-4	Halogen-Free csBGA	132	COM
LCMXO2-4000HE-5MG132C	4320	1.2 V	-5	Halogen-Free csBGA	132	COM
LCMXO2-4000HE-6MG132C	4320	1.2 V	-6	Halogen-Free csBGA	132	COM
LCMXO2-4000HE-4BG256C	4320	1.2 V	-4	Halogen-Free caBGA	256	COM
LCMXO2-4000HE-4MG184C	4320	1.2 V	-4	Halogen-Free csBGA	184	COM
LCMXO2-4000HE-5MG184C	4320	1.2 V	-5	Halogen-Free csBGA	184	COM
LCMXO2-4000HE-6MG184C	4320	1.2 V	-6	Halogen-Free csBGA	184	COM
LCMXO2-4000HE-5BG256C	4320	1.2 V	-5	Halogen-Free caBGA	256	COM
LCMXO2-4000HE-6BG256C	4320	1.2 V	-6	Halogen-Free caBGA	256	COM
LCMXO2-4000HE-4FTG256C	4320	1.2 V	-4	Halogen-Free ftBGA	256	COM
LCMXO2-4000HE-5FTG256C	4320	1.2 V	-5	Halogen-Free ftBGA	256	COM
LCMXO2-4000HE-6FTG256C	4320	1.2 V	-6	Halogen-Free ftBGA	256	COM
LCMXO2-4000HE-4BG332C	4320	1.2 V	-4	Halogen-Free caBGA	332	COM
LCMXO2-4000HE-5BG332C	4320	1.2 V	-5	Halogen-Free caBGA	332	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000ZE-1UWG49ITR ¹	2112	1.2 V	-1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1UWG49ITR50 ³	2112	1.2 V	-1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1UWG49ITR1K ²	2112	1.2 V	-1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1TG100I	2112	1.2 V	-1	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-2TG100I	2112	1.2 V	-2	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-3TG100I	2112	1.2 V	-3	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-1MG132I	2112	1.2 V	-1	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-2MG132I	2112	1.2 V	-2	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-3MG132I	2112	1.2 V	-3	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-1TG144I	2112	1.2 V	-1	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-2TG144I	2112	1.2 V	-2	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-3TG144I	2112	1.2 V	-3	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-1BG256I	2112	1.2 V	-1	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-2BG256I	2112	1.2 V	-2	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-3BG256I	2112	1.2 V	-3	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-1FTG256I	2112	1.2 V	-1	Halogen-Free ftBGA	256	IND
LCMXO2-2000ZE-2FTG256I	2112	1.2 V	-2	Halogen-Free ftBGA	256	IND
LCMXO2-2000ZE-3FTG256I	2112	1.2 V	-3	Halogen-Free ftBGA	256	IND

1. This part number has a tape and reel quantity of 5,000 units with a minimum order quantity of 10,000 units. Order quantities must be in increments of 5,000 units. For example, a 10,000 unit order will be shipped in two reels with one reel containing 5,000 units and the other reel with less than 5,000 units (depending on test yields). Unserviced backlog will be canceled.
2. This part number has a tape and reel quantity of 1,000 units with a minimum order quantity of 1,000. Order quantities must be in increments of 1,000 units. For example, a 5,000 unit order will be shipped as 5 reels of 1000 units each.
3. This part number has a tape and reel quantity of 50 units with a minimum order quantity of 50. Order quantities must be in increments of 50 units. For example, a 1,000 unit order will be shipped as 20 reels of 50 units each.